

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

|  |   |                                 |
|--|---|---------------------------------|
| In re application of: Lawrence Pileggi | ) |                                 |
|  | ) |                                 |
| Application No.: 10/707,205            | ) | Group Art Unit: 2138            |
|  | ) |                                 |
|  | ) | Examiner: Saqib Javaid Siddiqui |
|  | ) |                                 |
| Filed: November 26, 2003               | ) | Confirmation No.: 1204          |
|  | ) |                                 |
| Title: SYSTEM AND METHOD TO            | ) |                                 |
| TEST INTEGRATED CIRCUITS               | ) |                                 |
| ON A WAFER                             | ) |                                 |
|  | ) |                                 |

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Mail Stop: AF  
Commissioner for Patents  
PO Box 1450  
Alexandria, VA 22313-1450

***AMENDMENT AFTER FINAL ACTION UNDER 37 CFR §1.116***

Sir:

In response to the Office Action dated as mailed August 22, 2006, please amend the above-identified application as follows:

**There are no Amendments to the Specification.**

**Amendments to the Claims** are reflected in the listing of claims which begins on page 2 of this paper.

**Remarks** begin on page 15 of this paper.